

Measuring Low Energy Nuclear Recoil Ionization Yield with Thermal Neutron Capture

Nick Mast

University of Minnesota

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Overview

- Low energy NR ionization yield in Ge and Si
 - Who needs it?
 - Current measurements
- n-capture technique
- Experiment
 - CDMS SNOLAB HV detector
 - n-capture experiment design
 - Theoretical n-capture recoil signal
- n-flux measurement with Ge activation
- HV noise in Ge detector
- Preliminary results in Si
- Future plans

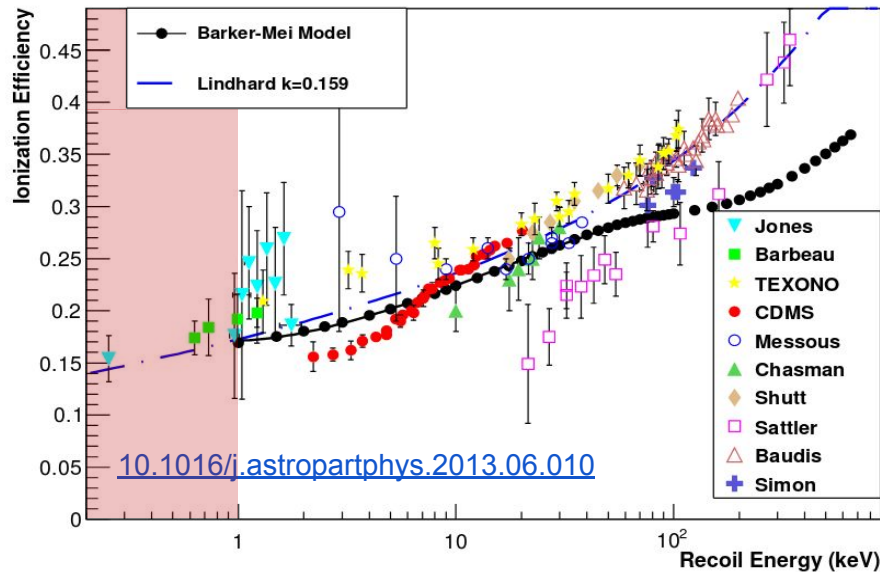
Experiments using NR in Ge/Si

Who relies on nuclear recoils (NR) in Ge/Si at $E \lesssim 1$ keV?

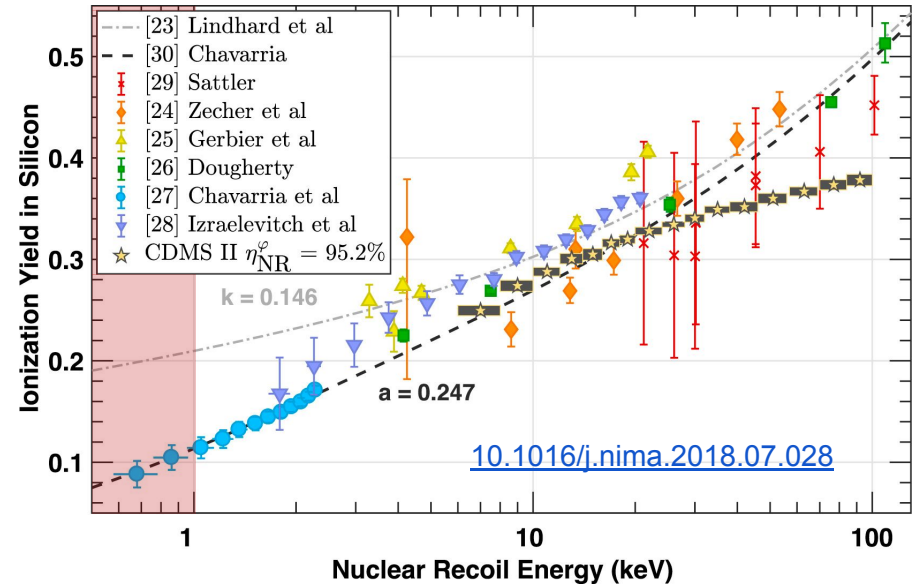
- Dark Matter (DM)
 - CDMS (Ge,Si)
 - DAMIC (Si)
 - Edelweiss (Ge)
 - CDEX (Ge)
 - ...
- Coherent Elastic Neutrino-Nucleus Scattering (CEvNS)
 - MIVER (Ge,Si)
 - CONUS (Ge)
 - CONNIE (Si)
 - TEXONO (Ge)
 - ν GeN (Ge)
 - Ricochet at Chooz (Ge)
 - ...

Low Energy NR Yield

Ge



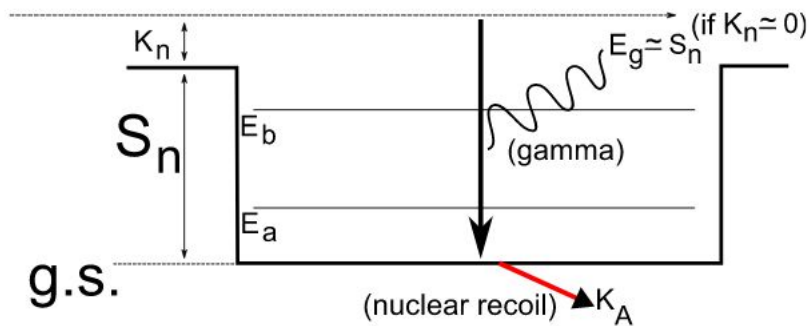
Si



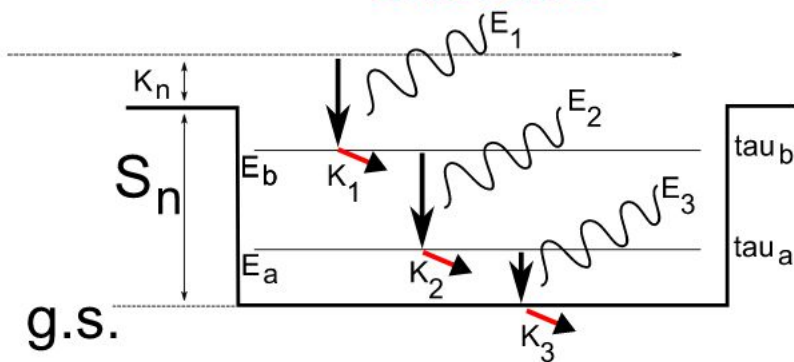
- NR produces less ionization for a given recoil energy, E_R
 - Ionization Yield, $Y = N_{NR}/N_{ER}$
 - Often use 2 different energy scales: E_{ee} and E_{nr}
- NR Yield is energy- and material-dependent
- **Not well known** at low energies (<1 keV)

n, γ NR Calibration Technique

Direct to Ground



Cascade



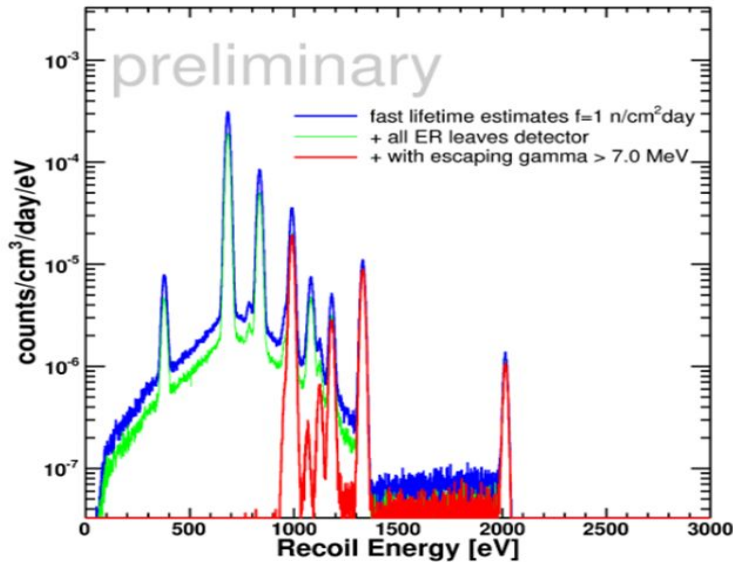
- Capture thermal neutrons on detector nuclei
- Decays result in **pure NR** (if gamma escapes)
- Cascade paths are quite complex (multiple gammas, lifetimes)



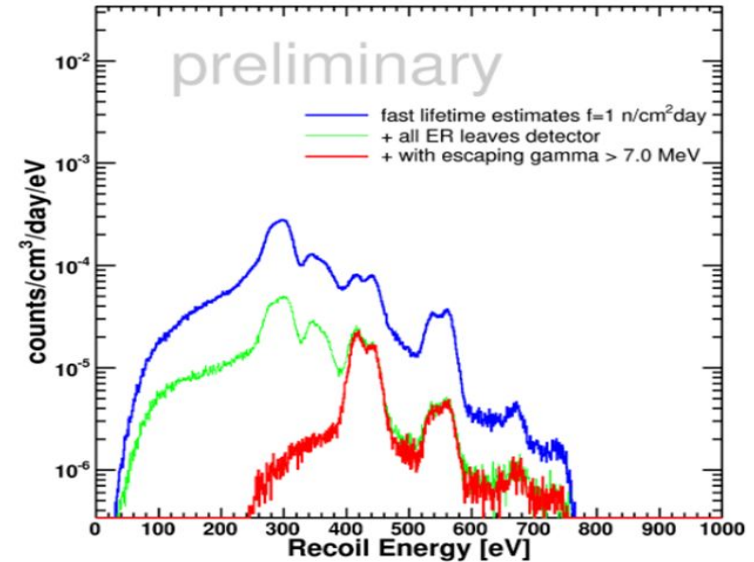
Theoretical NR Spectra

$$E_{Recoil} \simeq \frac{E_{\gamma}^2}{2M_N}$$

Silicon



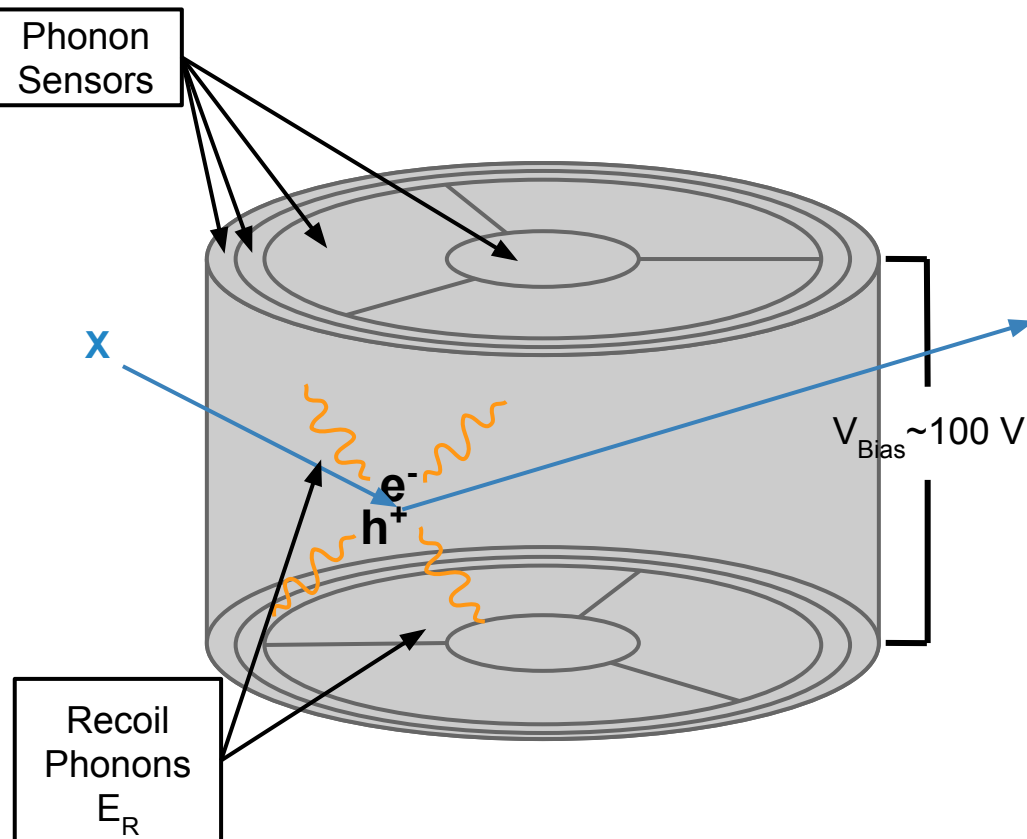
Germanium



All energy scales are NR, 60 eVnr resolution applied

- Measure this spectrum in E_{ee} to get ionization yield
- Detailed structure depends on nuclear levels, lifetimes, Fano factor, detector resolution

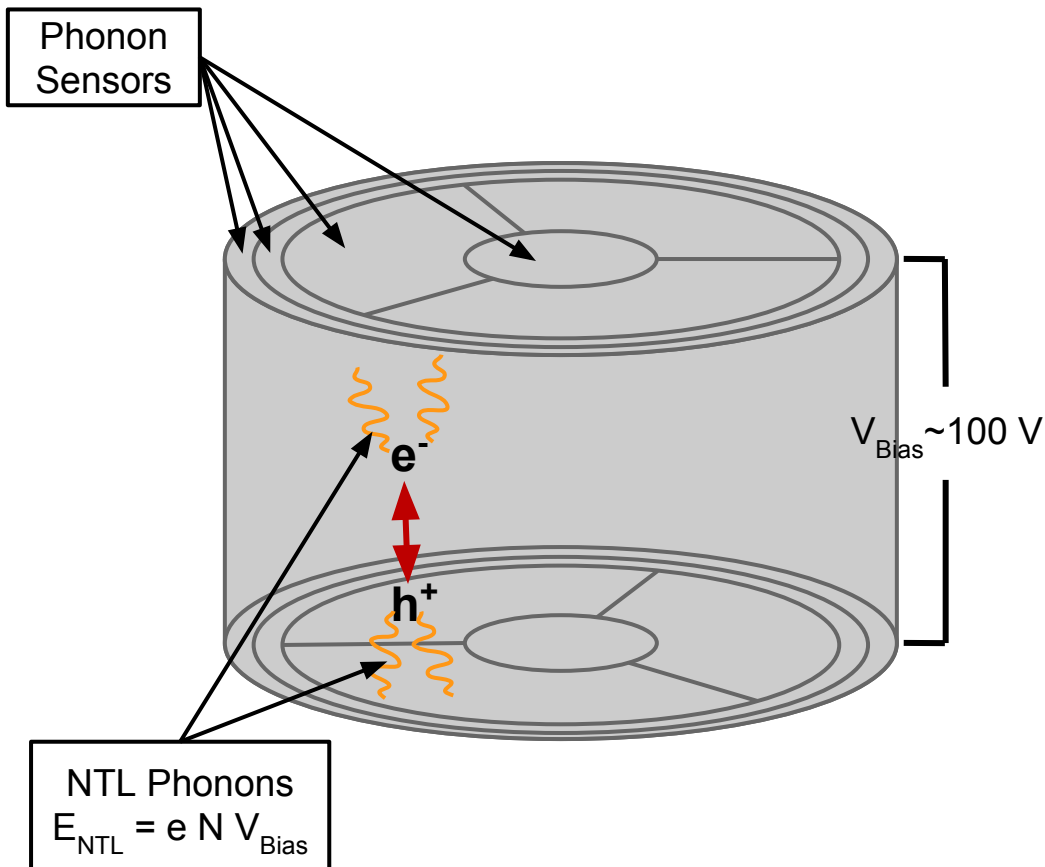
CDMS HV Detector



- Prototype Ge and Si detectors for CDMS SNOLAB
- TES-based phonon sensors
 - Operated at ~ 35 mK
- NTL Effect used to amplify charge signal
- Small energy resolution to see low mass DM

Measured Phonon Signal: $E_{Tot} = E_R + \dots$

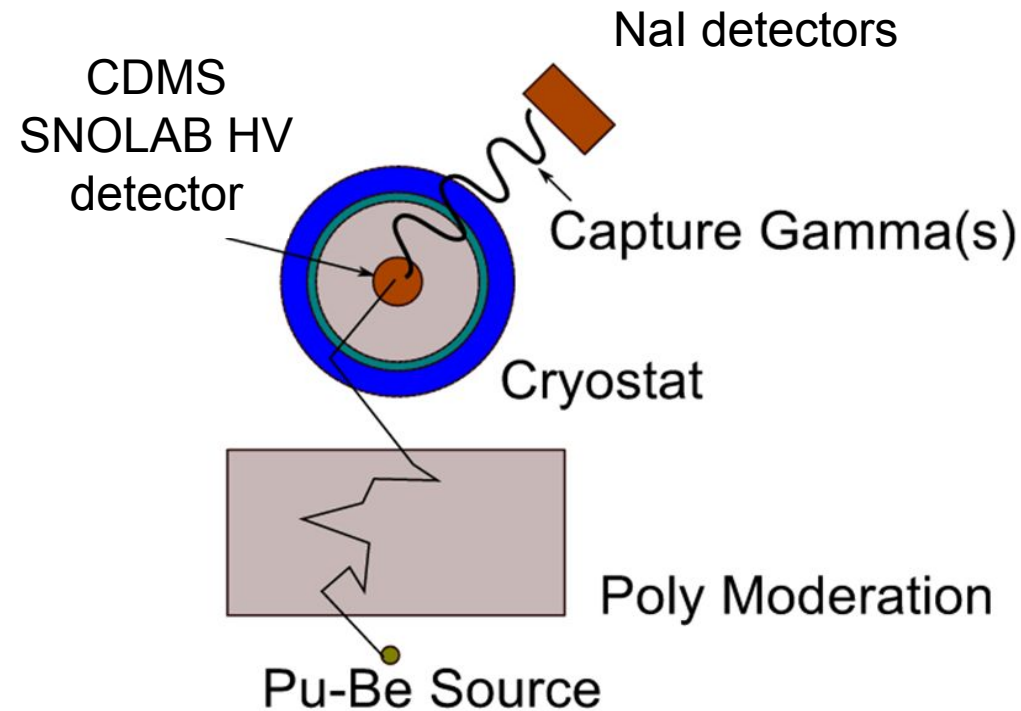
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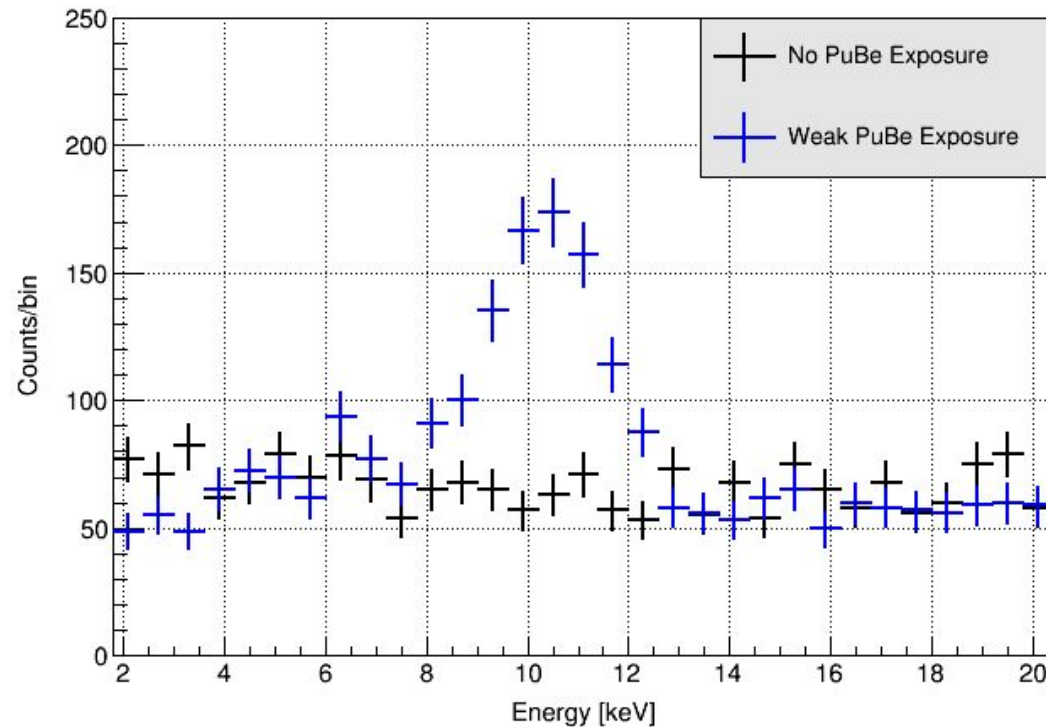
$$\text{Measured Phonon Signal: } E_{Tot} = E_R + e N V_{Bias} \approx e N V_{Bias}$$

Experimental Setup



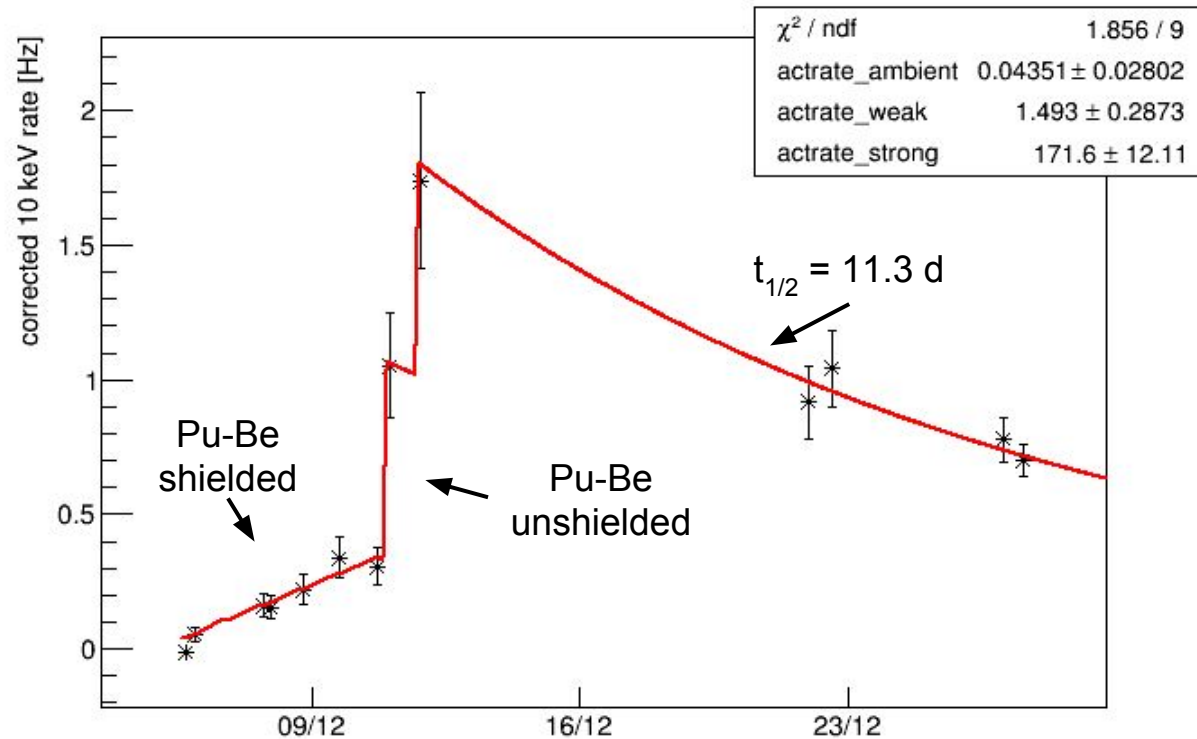
- 1Ci Pu-Be source provides $\sim 1 \times 10^6$ n/s
- ~ 1 m polyethylene for neutron moderation
- 30 cm of Pb (not pictured) for source gamma attenuation
- Nal detectors for \sim MeV gamma coincidence

n-flux measurement with Ge activation



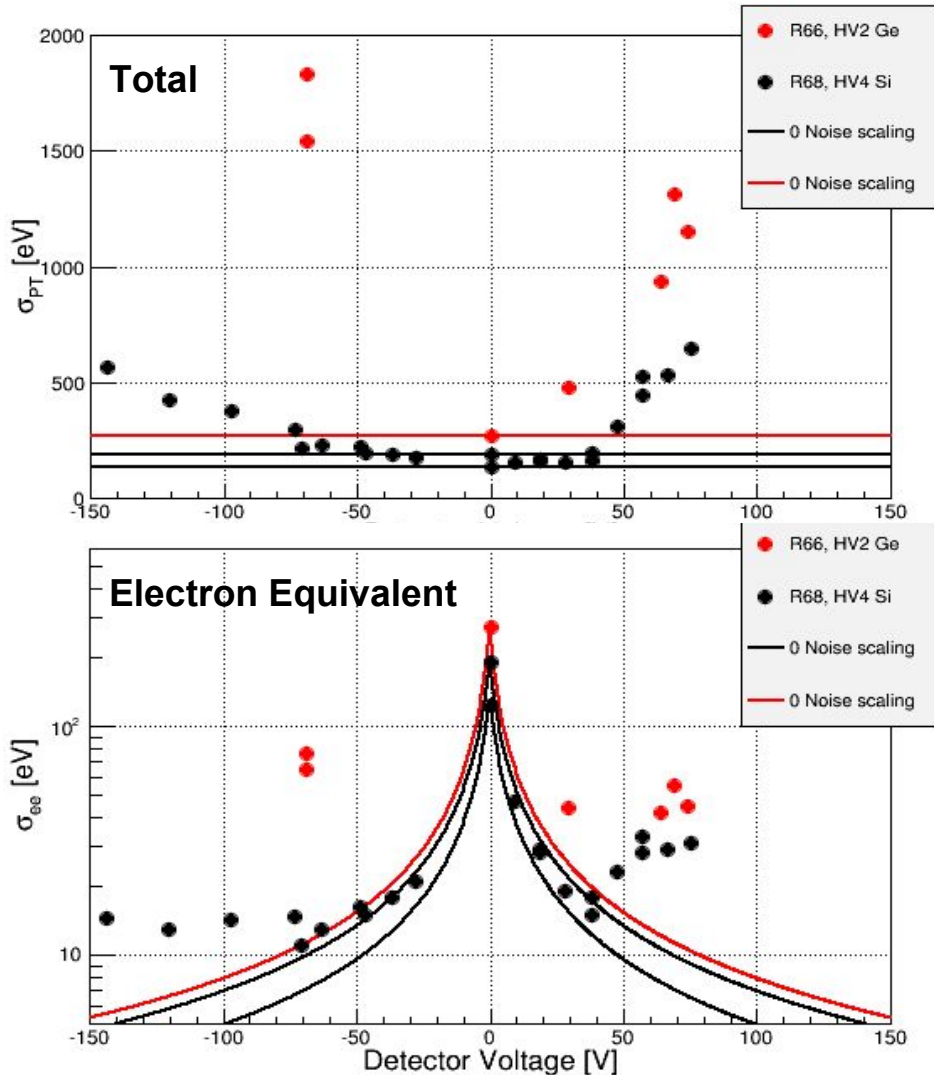
- n-capture on ^{70}Ge results in ER activation lines (10, 1, 0.1 keV_{ee})
- Activation rate depends on n capture cross section (~known), ^{71}Ge half life (known), n flux

n-flux measurement with Ge activation



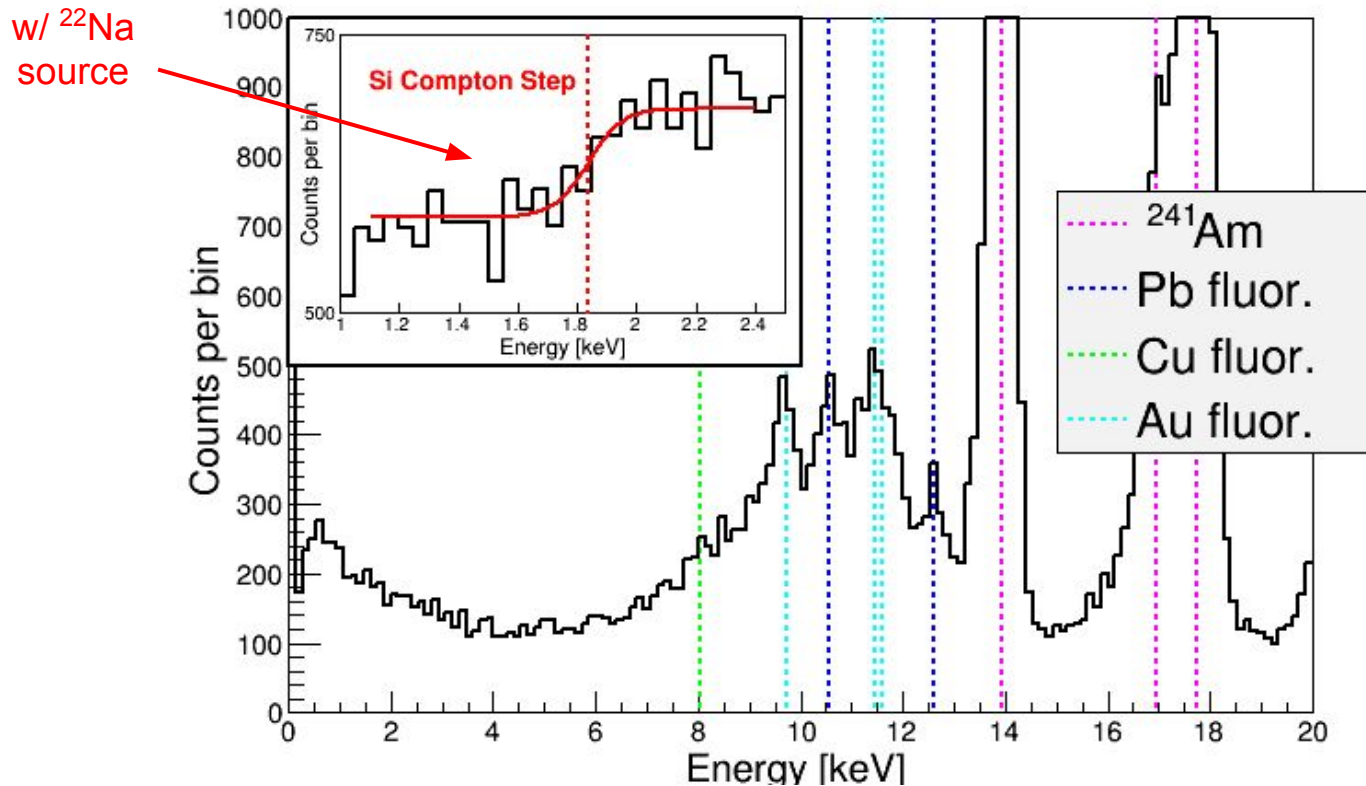
- Activation rate gives n-flux (Assuming $\sigma = 3.71 \text{ bn}$)
- Measured thermal n fluxes from $0.2 - 20 \text{ n/cm}^2/\text{s}$ with different source positions
 - Optimize source configuration
 - Benchmark simulations

HV Noise



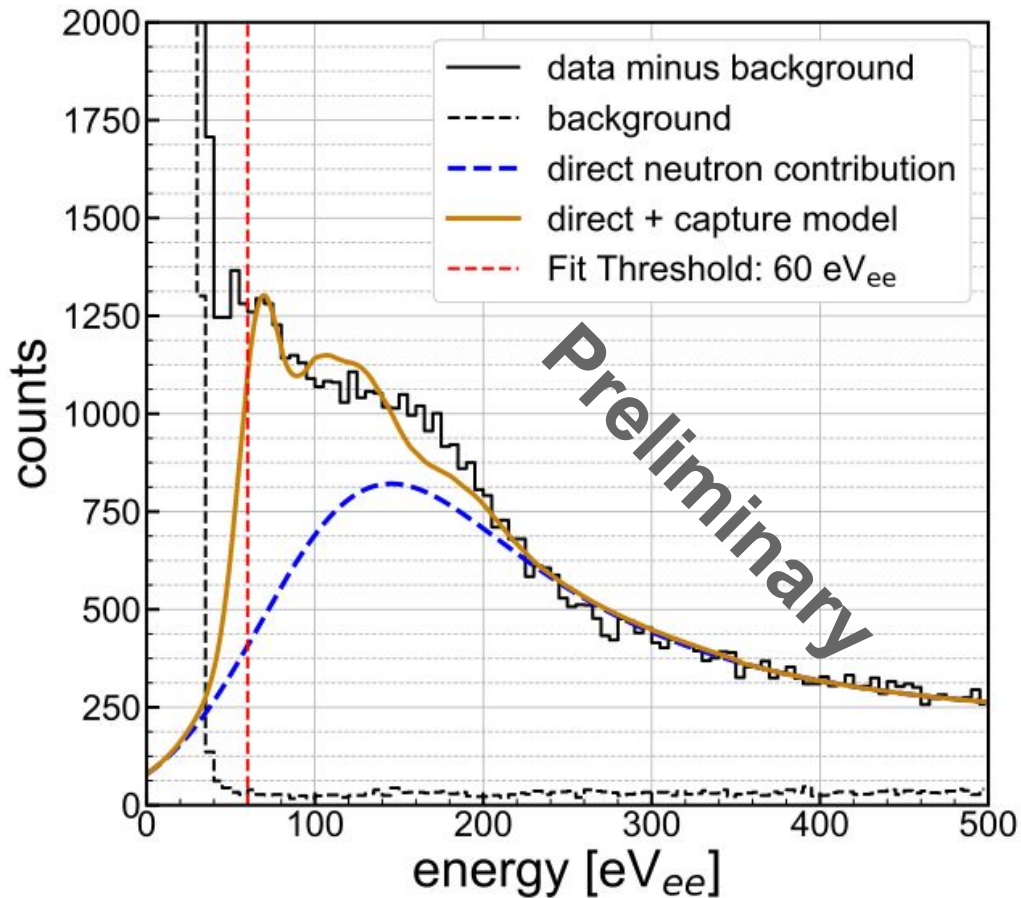
- Phonon signal $\propto V_{Bias}$
- HV related noise limits these detectors
 - Polarity dependent
 - Bulk detrapping vs. surface leakage?
 - Being studied in single-e/h sensitive chips
 - May be improved with IR shielding, contact-free electrode
- Observed lowest noise with Si CDMS HV detector at -125 V

Calibration in Si



- Calibrate using ^{241}Am , fluorescence lines, Compton edge, and Compton step

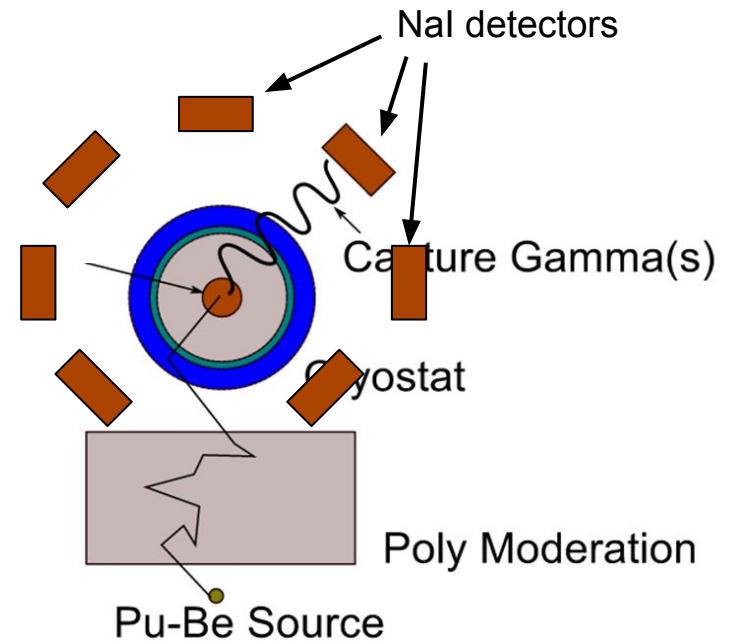
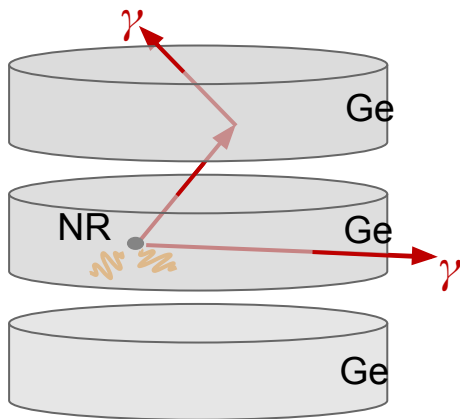
Encouraging Evidence in Si



- ~100 hrs of weak Pu-Be exposure
- $V_{\text{Bias}} = -125 \text{ V}$ ($\times 30$ phonon amplification)
- Signal consistent with known estimates of NR yield and flux
- Working to understand trigger/cut efficiencies, energy calibration, other systematics

Plans for Future Measurement

- Repeat with Ge
 - Contact-free electrode
 - Improved IR shielding
- Improve coincidence tagging
 - Higher NaI coverage
 - Detector stack?

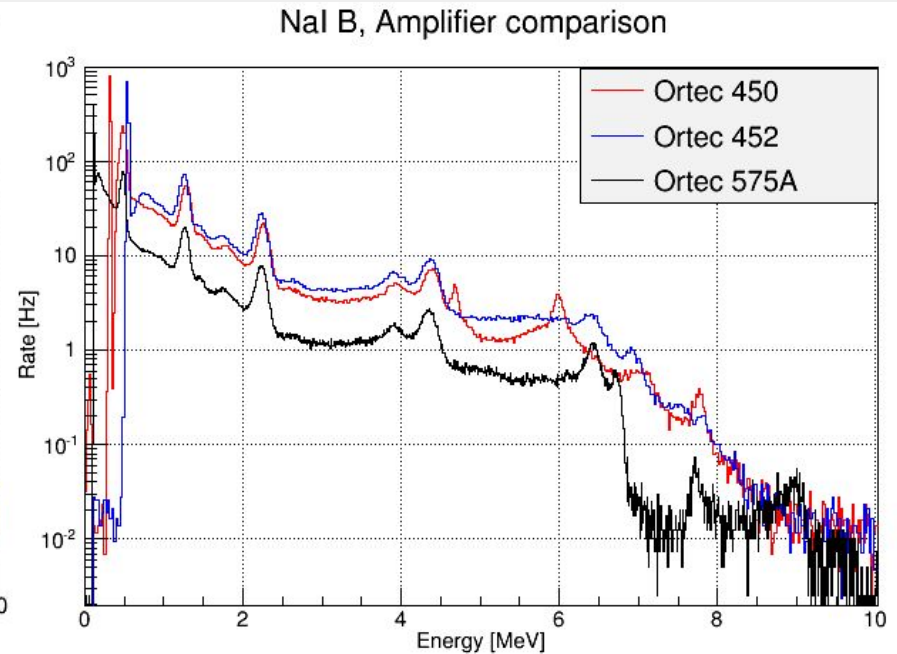
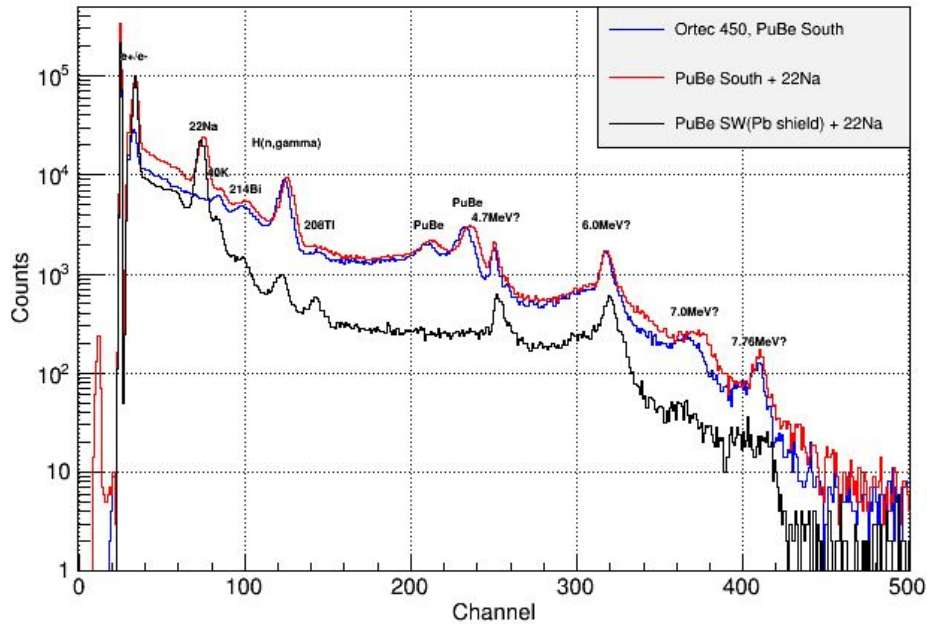


Summary

- Low energy NR ionization yield in Ge and Si needs to be understood
- Cryogenic phonon-based detectors are a good platform to make such a measurement
- n-capture technique provides rich spectral features
 - Low energy NRs
 - n-flux measurement with long lived states
- Preliminary evidence in Si
- Working toward improved measurements in Ge and Si

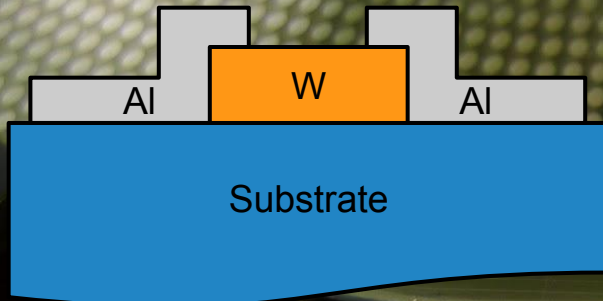
Backup Slides

NaI detectors



- Early results showed surprisingly little coincidence
- Spectra w/ funny amplifier resonances
- Amplifier saturation effects
- Need good ~ 10 MeV calibration features

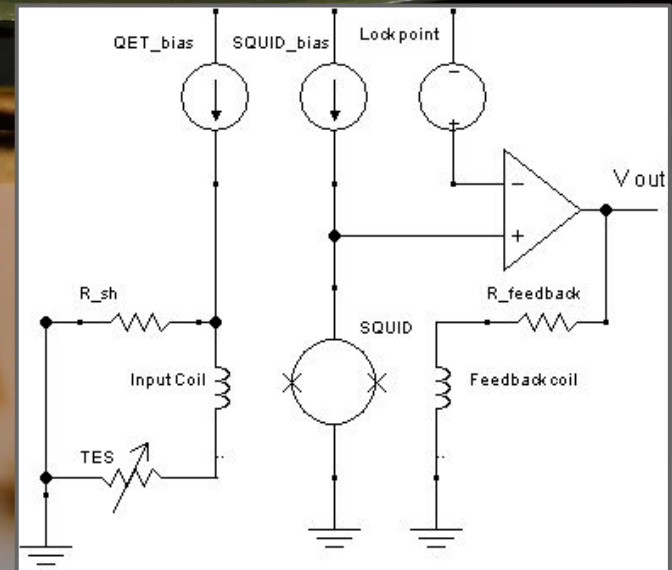
Phonon Sensors



- TES in ETF mode
- Voltage biased
- $P = V^2 / R(T) \Rightarrow$ stable at W 's TC

$$c_V \frac{dT}{dt} = P_{in} - \kappa(T^n - T_{crystal}^n)$$

- TES current change tracks absorbed phonon power
- Measure with SQUID-based amplifier



CDMS phonon circuit